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**INFORMATION DISCLOSURE STATEMENT BY APPLICANT****LIST OF REFERENCES CITED BY APPLICANT**

Applicant: Smit-Kingma et al.  
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Attorney Docket No.: C7695(V)  
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Group: 2877

**U.S. PATENT DOCUMENTS**

EXAM. INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
TR	2001/0042391 A1	11/01	Wobkemeier			
TR	2001/0049846 A1	12/01	Guzzi et al.			
TR	2002/0113212 A1	8/02	Meglen et al.			

**FOREIGN PATENT DOCUMENTS**

EXAM. INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO
TR	01/46509 A1	6/01	WO			
TR	199 20 592 A	11/00	DE			
TR	0 612 996 A2	8/94	EP			

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)**

TR	European Search Report Application No. EP 02 08 0330 dated April 4, 2003
TR	Bickel A.: "Nir Analyzers Earn Their Place in Process Control", I & CS - Industrial and Process Control Magazine, Chilton Company, Radnor, PA, US, Vol. 62, No. 7 (7/89) pages 45-48, XP000072786)
Examiner:	TR Date Considered: 3/3/06

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.